

**PATENT APPLICATION**

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re application of

Docket No: Q66584

Masayuki NAYA, et al.

Appln. No.: 10/053,585

Confirmation No.: 3468

Group Art Unit: 1641

Filed: January 24, 2002

Examiner: Christopher L. Chin

For: SURFACE PLASMON RESONANCE MEASURING CHIP AND METHOD OF  
MANUFACTURE THEREOF

**SUBMISSION UNDER 37 C.F.R. § 1.114(c)**

**MAIL STOP RCE**

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

Sir:

In response to the Office Action dated July 19, 2006, please amend the above-identified application as follows on the accompanying pages.